FDD2582

MOSFET, N-Channel, POWERTRENCH®

150 V, 21 A, 66 mΩ

Features

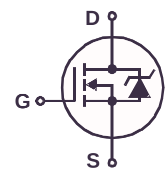
- $r_{DS(ON)}$ = 58 mΩ (Typ.), V_{GS} = 10 V, I_D = 7 A
- Q_g(tot) = 19 nC (Typ.), V_{GS} = 10 V
- Low Miller Charge
- Low Q_{RR} Body Diode
- UIS Capability (Single Pulse and Repetitive Pulse)
- These Devices are Pb−Free, Halide Free and are RoHS Compliant

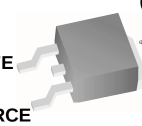
Applications

- DC/DC Converters and Off−Line UPS
- Distributed Power Architectures and VRMs
- Primary Switch for 24 V and 48 V Systems
- High Voltage Synchronous Rectifier
- Direct Injection / Diesel Injection Systems
- 42 V Automotive Load Control
- Electronic Valve Train System

ON Semiconductor®

www.onsemi.com





DPAk3 (TO−252 3 LD)
CASE 369AS

MARKING DIAGRAM

$Y&Z&3&K
FDD2582

$Y	= ON Semiconductor Logo
&Z	= Assembly Plant Code
&3	= Numeric Date Code
&K	= Lot Code
FDD2582	= Specific Device Code

ORDERING INFORMATION

See detailed ordering and shipping information on page 2 of this data sheet.

MOSFET MAXIMUM RATINGS (T_C = 25°C, Unless otherwise noted)

Symbol	Parameter		Ratings	Units
V_{DSS}	Drain to Source Voltage		150	V
V_{GS}	Gate to Source Voltage		±20	V
I_D	Drain Current	−Continuous (T_C = 25°C, V_{GS} = 10 V)	21	A
		−Continuous (T_C = 100°C, V_{GS} = 10 V)	15	
		−Continuous (T_{amb} = 25°C, V_{GS} = 10 V, $R_{θJA}$ = 52°C/W)	3.7	
		−Pulsed	See Figure 4	
E_{AS}	Single Pulse Avalanche Energy (Note 1)		59	mJ
P_D	Power Dissipation		95	W
	Derate above 25°C		0.63	W/°C
T_J, T_{STG}	Operating and Storage Temperature		−55 to 175	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

1. Starting T_J = 25°C, L = 1.17 mH, I_{AS} = 10 A.

THERMAL CHARACTERISTICS

Symbol	Parameter	Ratings	Units
$R_{θJC}$	Thermal Resistance, Junction to Case TO−252	1.58	°C/W
$R_{θJA}$	Thermal Resistance, Junction to Ambient TO−252	100	
$R_{θJA}$	Thermal Resistance, Junction to Ambient TO−252, 1 in^2 copper pad area	52	

PACKAGE MARKING AND ORDERING INFORMATION

Device Marking	Device	Package	Shipping†
FDD2582	FDD2582	DPAK3 (TO−252 3 LD) (Pb−Free, Halide Free)	2500 units / Tape & Reel

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D

ELECTRICAL CHARACTERISTICS (T_C = 25°C unless otherwise noted)

Symbol	Parameter	Test Conditions	Min	Typ	Max	Units
OFF CHARACTERISTICS						
BV_{DSS}	Drain to Source Breakdown Voltage	I_D = 250 μA, V_{GS} = 0 V	150			V
I_{DSS}	Zero Gate Voltage Drain Current	V_{DS} = 120 V, V_{GS} = 0 V V_{DS} = 120 V, V_{GS} = 0 V, T_C = 150°C			1 250	μA
I_{GSS}	Gate to Source Leakage Current	V_{GS} = ±20 V			±100	nA
ON CHARACTERISTICS						
$V_{GS(TH)}$	Gate to Source Threshold Voltage	V_{GS} = V_{DS}, I_D = 250 μA	2		4	V
$r_{DS(on)}$	Drain to Source On Resistance	I_D = 7 A, V_{GS} = 10 V I_D = 4 A, V_{GS} = 6 V I_D = 7 A, V_{GS} = 10 V, T_C = 150°C		0.058 0.066 0.151	0.066 0.099 0.172	Ω
DYNAMIC CHARACTERISTICS						
C_{ISS}	Input Capacitance	V_{DS} = 25 V, V_{GS} = 0 V, f = 1 MHz		1295		pF
C_{OSS}	Output Capacitance			145		pF
C_{RSS}	Reverse Transfer Capacitance			30		pF
$Q_{g(TOT)}$	Total Gate Charge at 10 V	V_{GS} = 0 V to 10 V; V_{DD} = 75 V, I_D = 7 A, I_g = 1.0 mA		19	25	nC
$Q_{g(TH)}$	Threshold Gate Charge	V_{GS} = 0 V to 4.5 V		2.4	3.2	nC
Q_{gs}	Gate to Source Gate Charge			6.2		nC
Q_{gs2}	Gate Charge Threshold to Plateau			3.8		nC
Q_{gd}	Gate to Drain “Miller” Charge			4.2		nC
RESISTIVE SWITCHING CHARACTERISTICS (V_{GS} = 10 V)						
t_{ON}	Turn−On Time	V_{DD} = 75 V, I_D = 7 A V_{GS} = 10 V, R_{GS} = 16 Ω			41	ns
$t_{d(ON)}$	Turn−On Delay Time			8		ns
t_r	Rise Time			19		ns
$t_{d(OFF)}$	Turn−Off Delay Time			32		ns
t_f	Fall Time			19		ns
t_{OFF}	Turn−Off Time				77	ns
DRAIN−SOURCE DIODE CHARACTERISTICS						
V_{SD}	Source to Drain Diode Voltage	I_{SD} = 7 A I_{SD} = 4 A			1.25 1.0	V
t_{rr}	Reverse Recovery Time	I_{SD} = 7 A, $\Delta I_{SD}/\Delta t$ = 100 A/μs			67	ns
Q_{RR}	Reverse Recovery Charge	I_{SD} = 7 A, $\Delta I_{SD}/\Delta t$ = 100 A/μs			134	nC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

TYPICAL CHARACTERISTICS T_C = 25°C unless otherwise noted.

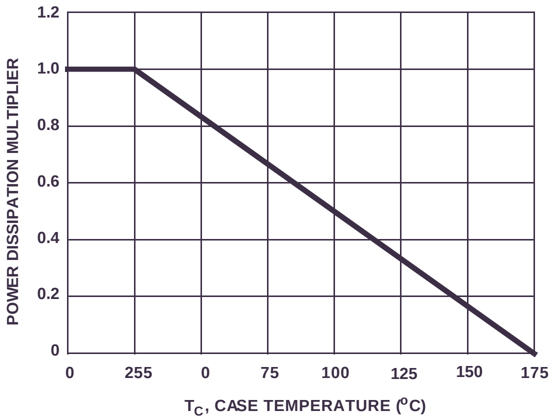


Figure 1. Normalized Power Dissipation vs. Ambient Temperature

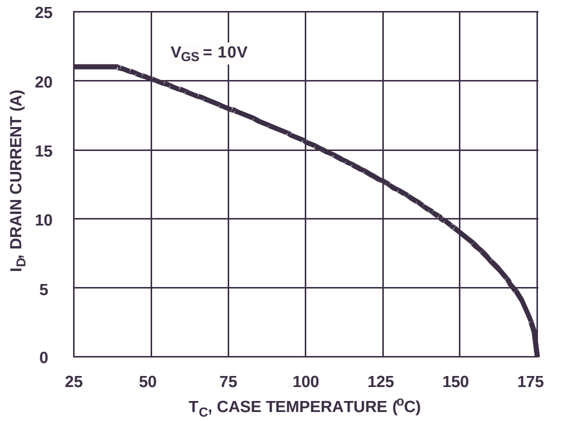


Figure 2. Maximum Continuous Drain Current vs. Case Temperature

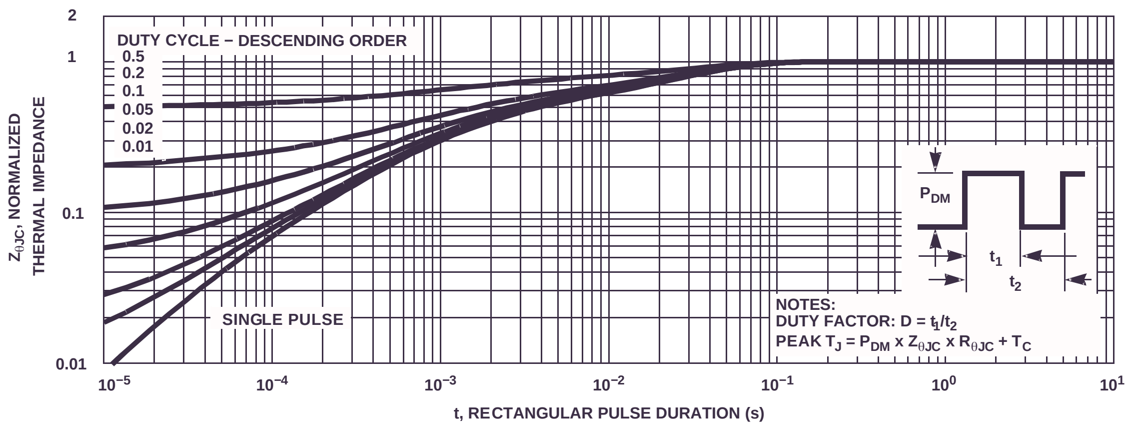


Figure 3. Normalized Maximum Transient Thermal Impedance

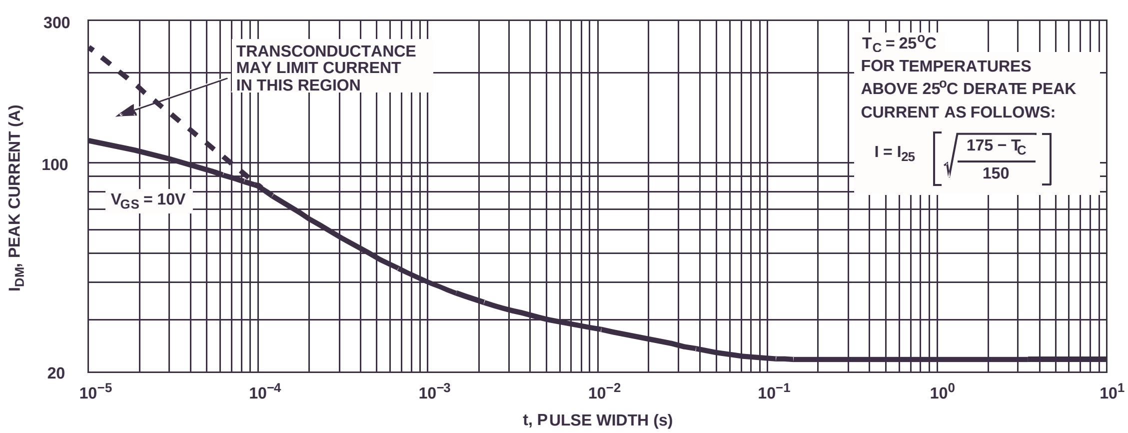


Figure 4. Peak Current Capability

TYPICAL CHARACTERISTICS T_C = 25°C unless otherwise noted.

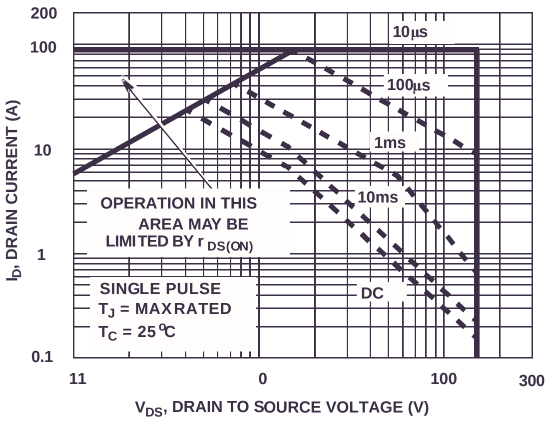
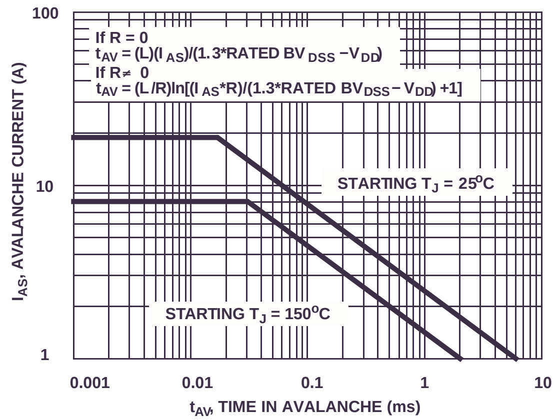


Figure 5. Forward Bias Safe Operating Area



Note: Refer to Application Notes AN7514 and AN7515

Figure 6. Unclamped Inductive Switching Capability

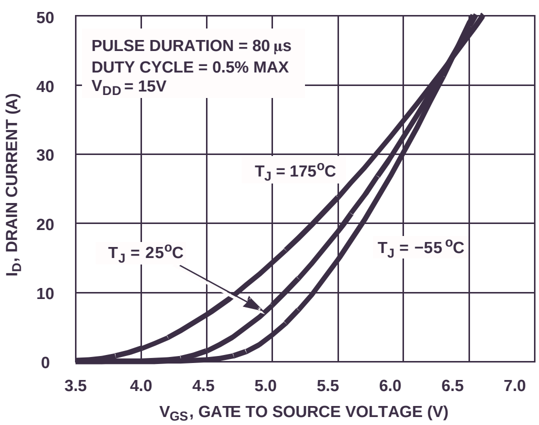


Figure 7. Transfer Characteristics

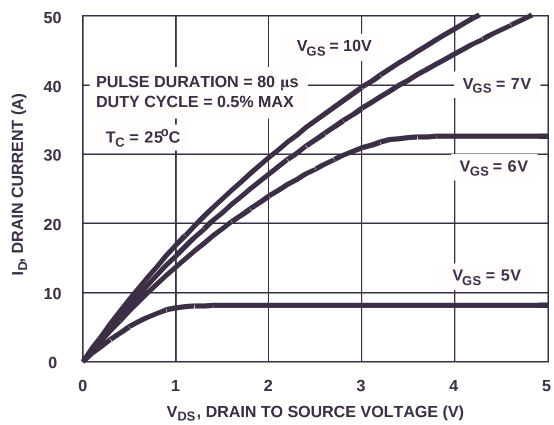


Figure 8. Saturation Characteristics

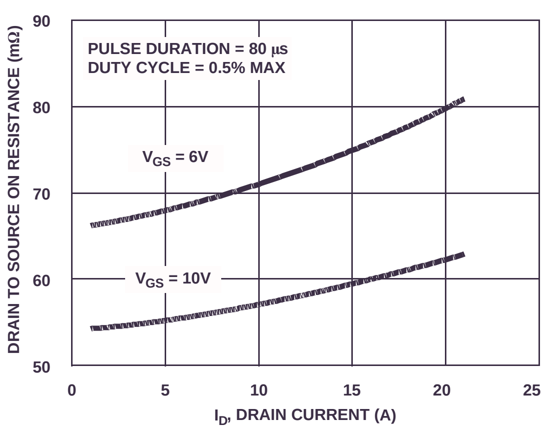


Figure 9. Drain to Source On Resistance vs. Drain Current

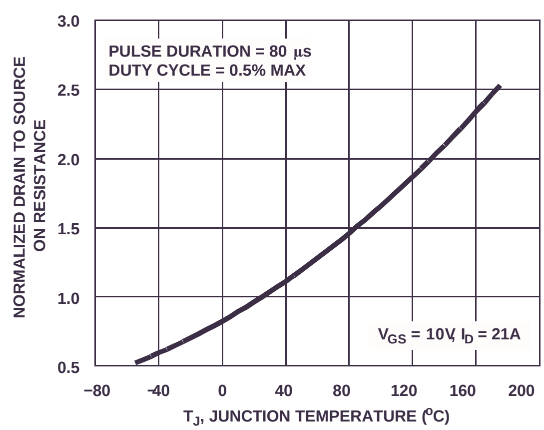


Figure 10. Normalized Drain to Source On Resistance vs. Junction Temperature

TYPICAL CHARACTERISTICS T_C = 25°C unless otherwise noted.

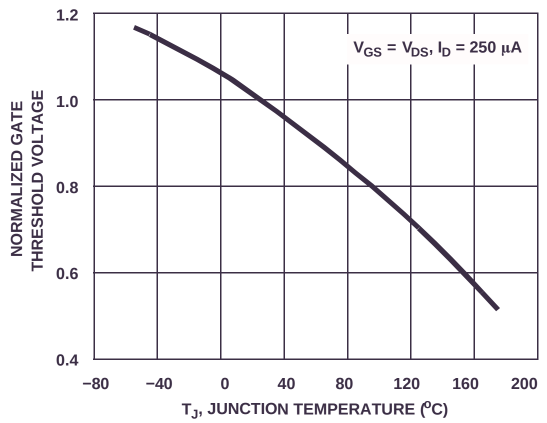


Figure 11. Normalized Gate Threshold vs. Junction Temperature

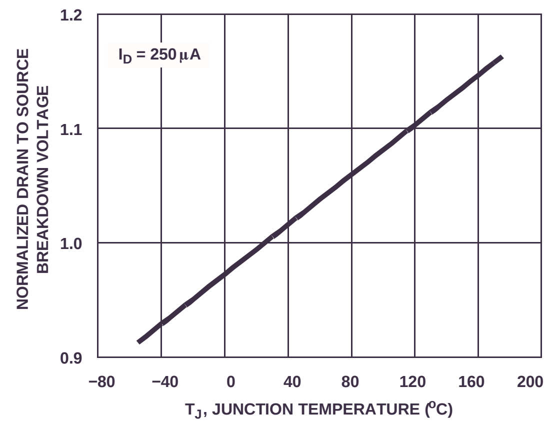


Figure 12. Normalized Drain to Source Breakdown Voltage vs. Junction Temperature

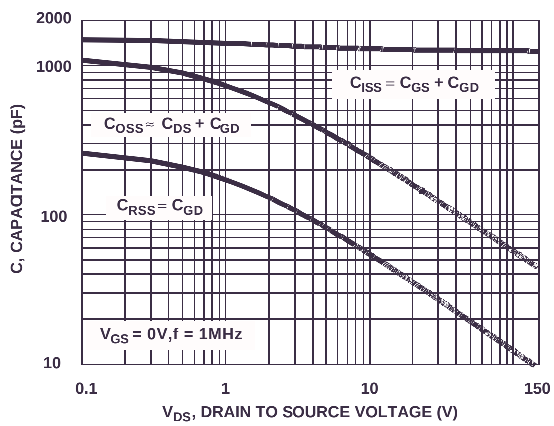


Figure 13. Capacitance vs. Drain to Source Voltage

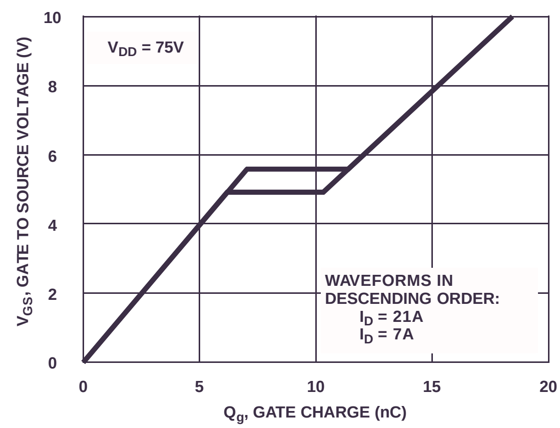


Figure 14. Cate Charge Waveforms for Constant Gate Currents

TEST CIRCUITS AND WAVEFORMS

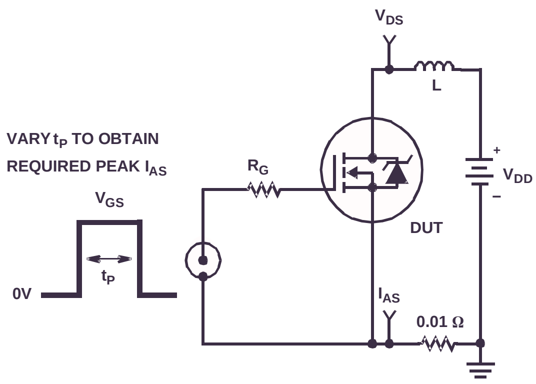


Figure 15. Unclamped Energy Test Circuit

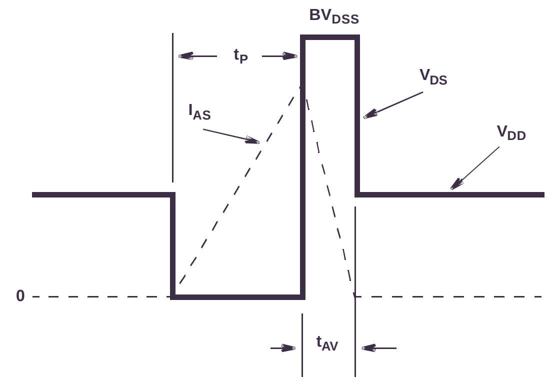


Figure 16. Unclamped Energy Waveforms

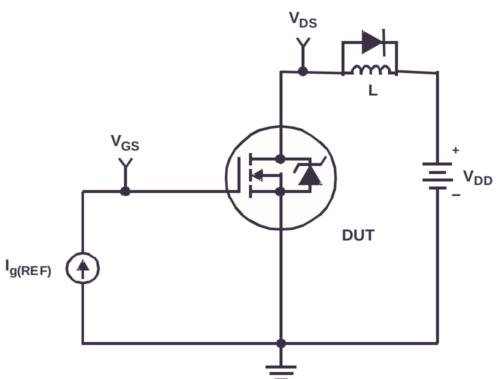


Figure 17. Gate Charge Test Circuit

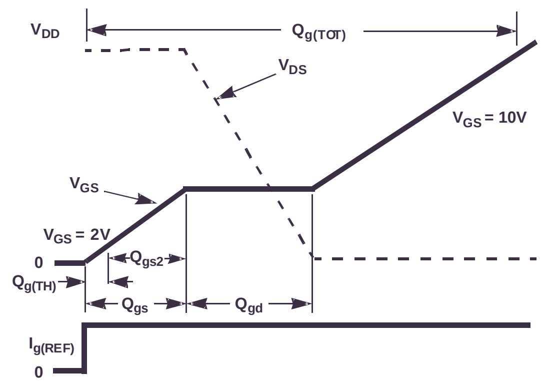


Figure 18. Gate Charge Waveforms

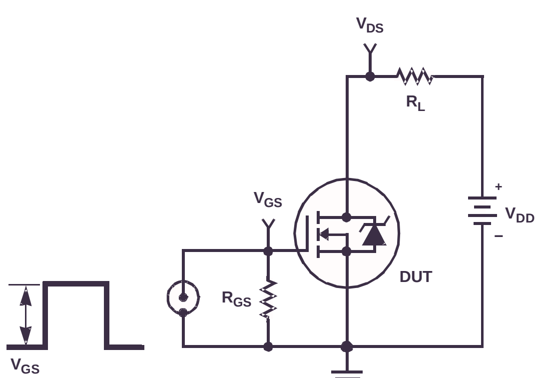


Figure 19. Switching Time Test Circuit

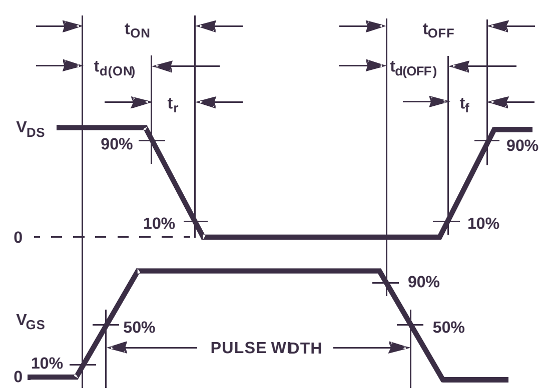


Figure 20. Switching Time Waveforms

Thermal Resistance vs. Mounting Pad Area

The maximum rated junction temperature, T_{JM}, and the thermal resistance of the heat dissipating path determines the maximum allowable device power dissipation, P_{DM}, in an application. Therefore, the application's ambient temperature, T_A (°C), and thermal resistance $R_{\theta JA}$ (°C/W) must be reviewed to ensure that T_{JM} is never exceeded. Equation 1 mathematically represents the relationship and serves as the basis for establishing the rating of the part.

$$P_{DM} = \frac{(T_{JM} - T_A)}{R_{\theta JA}} \quad \text{(eq. 1)}$$

In using surface mount devices such as the TO−252 package, the environment in which it is applied will have a significant influence on the part's current and maximum power dissipation ratings. Precise determination of P_{DM} is complex and influenced by many factors:

1. Mounting pad area onto which the device is attached and whether there is copper on one side or both sides of the board.
2. The number of copper layers and the thickness of the board.
3. The use of external heat sinks.
4. The use of thermal vias.
5. Air flow and board orientation.
6. For non steady state applications, the pulse width, the duty cycle and the transient thermal response of the part, the board and the environment they are in.

ON Semiconductor provides thermal information to assist the designer's preliminary application evaluation. Figure 21 defines the $R_{\theta JA}$ for the device as a function of the top copper (component side) area. This is for a horizontally positioned FR−4 board with 1oz copper after 1000 seconds of steady state power with no air flow. This graph provides the necessary information for calculation of the steady state junction temperature or power dissipation. Pulse applications can be evaluated using the ON Semiconductor device Spice thermal model or manually utilizing the normalized maximum transient thermal impedance curve.

Thermal resistances corresponding to other copper areas can be obtained from Figure 21 or by calculation using Equation 2 or 3. Equation 2 is used for copper area defined in inches square and equation 3 is for area in centimeters square. The area, in square inches or square centimeters is the top copper area including the gate and source pads.

$$R_{\theta JA} = 33.32 + \frac{23.84}{(0.268 + \text{Area})} \quad \text{Area in [in}^2\text{]} \quad \text{(eq. 2)}$$

$$R_{\theta JA} = 33.32 + \frac{154}{(1.73 + \text{Area})} \quad \text{Area in [cm}^2\text{]} \quad \text{(eq. 3)}$$

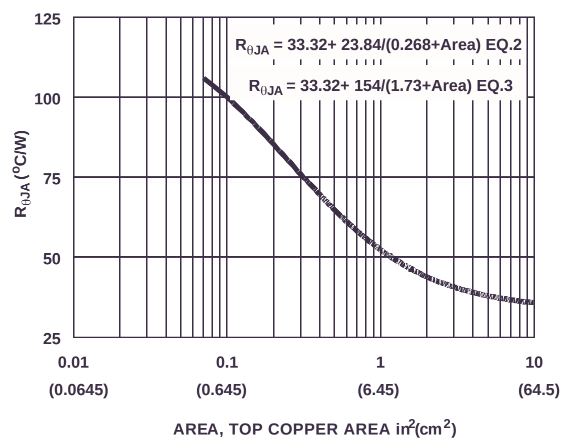
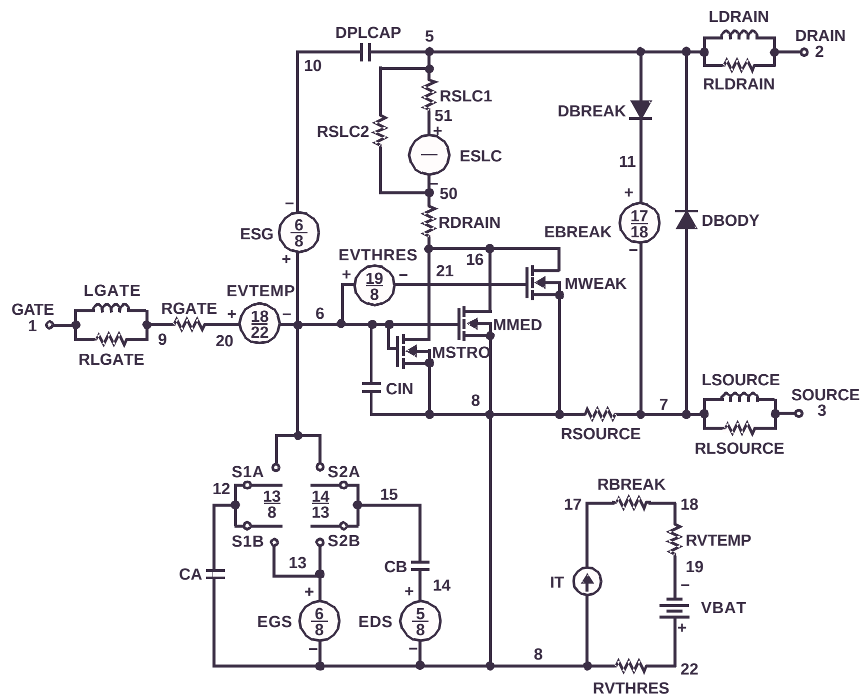


Figure 21. Thermal Resistance vs. Mounting Pad Area

PSPICE Electrical Model




```
.SUBCKT FDD2582  2 1 3 ;        rev July 2002
Ca  12  8 4e-10
Cb  15  14 4.6e-10
Cin  6  8 1.24e−9

Dbody 7 5 DbodyMOD
Dbreak 5 11 DbreakMOD
Dplcap 10 5 DplcapMOD

Ebreak 11 7 17 18 160.4
Eds 14 8 5 8 1
Egs 13 8 6 8 1
Esg 6 10 6 8 1
Evthres 6 21 19 8 1
Evtemp 20 6 18 22 1

It 8 17 1

Lgate 1 9 4.88e-9
Ldrain 2 5 1.0e-9
Lsource 3 7 2.24e-9

RLgate 1 9 48.8
RLdrain 2 5 10
RLsource 3 7 22.4

Mmed 16 6 8 8 MmedMOD
Mstro 16 6 8 8 MstroMOD
Mweak 16 21 8 8 MweakMOD

Rbreak 17 18 RbreakMOD 1
Rdrain 50 16 RdrainMOD 37e-3
Rgate 9 20 1.8
RSLC1 5 51 RSLCMOD 1.0e-6
RSLC2 5 50 1.0e3
Rsource 8 7 RsourceMOD 11.9e-3
Rvthres 22 8 RvthresMOD 1
Rvtemp 18 19 RvtempMOD 1
S1a 6 12 13 8 S1AMOD
S1b 13 12 13 8 S1BMOD
S2a 6 15 14 13 S2AMOD
S2b 13 15 14 13 S2BMOD

Vbat 22 19 DC 1

ESLC 51 50  VALUE={(V(5,51)/ABS(V(5,51)))*(PWR(V(5,51)/(1e-6*42),2.5))}

.MODEL DbodyMOD D (IS=2.3E-12 RS=5.3e-3 TRS1=2.2e-3 TRS2=4.5e-7
+ CJO=8.8e-10 M=0.64 TT=3.8e-8 XTI=4.2)
.MODEL DbreakMOD D (RS=0.4 TRS1=1.4e-3 TRS2=-5e-5)
.MODEL DplcapMOD D (CJO=2.75e−10 IS=1.0e−30 N=10 M=0.67)

.MODEL MmedMOD NMOS (VTO=3.76 KP=2.7 IS=1e-30 N=10 TOX=1 L=1u W=1u RG=1.64)
.MODEL MstroMOD NMOS (VTO=4.25 KP=30 IS=1e-30 N=10 TOX=1 L=1u W=1u)
.MODEL MweakMOD NMOS (VTO=3.2 KP=0.068 IS=1e-30 N=10 TOX=1 L=1u W=1u RG=16.4 RS=0.1)

.MODEL RbreakMOD RES (TC1=1.1e-3 TC2=-1.1e-8)
.MODEL RdrainMOD RES (TC1=1.0e-2 TC2=2.6e-5)
.MODEL RSLCMOD RES (TC1=2.7e-3 TC2=2.0e-6)
.MODEL RsourceMOD RES (TC1=1.0e-3 TC2=1.0e-6)
.MODEL RvthresMOD RES (TC1=-3.9e-3 TC2=-1.7e-5)
.MODEL RvtempMOD RES (TC1=-3.7e-3 TC2=1.9e-6)

.MODEL S1AMOD VSWITCH (RON=1e-5 ROFF=0.1 VON=-5.0 VOFF=-2.0)
.MODEL S1BMOD VSWITCH (RON=1e-5 ROFF=0.1 VON=-2.0 VOFF=-5.0)
.MODEL S2AMOD VSWITCH (RON=1e-5 ROFF=0.1 VON=-0.4 VOFF=0.3)
.MODEL S2BMOD VSWITCH (RON=1e-5 ROFF=0.1 VON=0.3 VOFF=-0.4)

.ENDS
```

Note: For further discussion of the PSPICE model, consult **A New PSPICE Sub−Circuit for the Power MOSFET Featuring Global Temperature Options**; IEEE Power Electronics Specialist Conference Records, 1991, written by William J. Hepp and C. Frank Wheatley.

Figure 22. PSPICE Electrical Model

SABER Electrical Model

```
REV July 2002
ttemplate FDD2582 n2,n1,n3
electrical n2,n1,n3
{
var i iscl
dp..model dbodymod = (isl=2.3e-12,rs=5.3e-3,trs1=2.2e-3,trs2=4.5e-7,cjo=8.8e-10,m=0.64,tt=3.8e-8,xti=4.2)
dp..model dbreakmod = (rs=0.4,trs1=1.4e-3,trs2=-5.0e-5)
dp..model dplcapmod = (cjo=2.75e-10,isl=10.0e-30,nl=10,m=0.67)
m..model mmedmod = (type=_n,vto=3.76,kp=2.7,is=1e-30, tox=1)
m..model mstrongmod = (type=_n,vto=4.25,kp=30,is=1e-30, tox=1)
m..model mweakmod = (type=_n,vto=3.2,kp=0.068,is=1e-30, tox=1,rs=0.1)
sw_vcsp..model s1amod = (ron=1e-5,roff=0.1,von=-5.0,voff=-2.0)
sw_vcsp..model s1bmod = (ron=1e-5,roff=0.1,von=-2.0,voff=-5.0)
sw_vcsp..model s2amod = (ron=1e-5,roff=0.1,von=-0.4,voff=0.3)
sw_vcsp..model s2bmod = (ron=1e-5,roff=0.1,von=0.3,voff=-0.4)
c.ca n12 n8 = 4e-10
c.cb n15 n14 = 4.6e-10
c.cin n6 n8 = 1.24e-9

dp.dbody n7 n5 = model=dbodymod
dp.dbreak n5 n11 = model=dbreakmod
dp.dplcap n10 n5 = model=dplcapmod

spe.ebreak n11 n7 n17 n18 = 160.4
spe.eds n14 n8 n5 n8 = 1
spe.egs n13 n8 n6 n8 = 1
spe.esg n6 n10 n6 n8 = 1
spe.evthres n6 n21 n19 n8 = 1
spe.evtemp n20 n6 n18 n22 = 1

i.it n8 n17 = 1

l.lgate n1 n9 = 4.88e-9
l.ldrain n2 n5 = 1.0e-9
l.lsource n3 n7 = 2.24e–9

res.rlgate n1 n9 = 48.8
res.rldrain n2 n5 = 10
res.rlsource n3 n7 = 22.4

m.mmed n16 n6 n8 n8 = model=mmedmod, l=1u, w=1u
m.mstrong n16 n6 n8 n8 = model=mstrongmod, l=1u, w=1u
m.mweak n16 n21 n8 n8 = model=mweakmod, l=1u, w=1u

res.rbreak n17 n18 = 1, tc1=1.1e-3,tc2=-1.1e-8
res.rdrain n50 n16 = 37e-3, tc1=1.0e-2,tc2=2.6e-5
res.rgate n9 n20 = 1.8
res.rslc1 n5 n51 = 1.0e-6, tc1=2.7e-3,tc2=2.0e-6
res.rslc2 n5 n50 = 1.0e3
res.rsource n8 n7 = 11.9e-3, tc1=1.0e-3,tc2=1.0e-6
res.rvthres n22 n8 = 1, tc1=-3.9e-3,tc2=-1.7e-5
res.rvtemp n18 n19 = 1, tc1=-3.7e-3,tc2=1.9e-6
sw_vcsp.s1a n6 n12 n13 n8 = model=s1amod
sw_vcsp.s1b n13 n12 n13 n8 = model=s1bmod
sw_vcsp.s2a n6 n15 n14 n13 = model=s2amod
sw_vcsp.s2b n13 n15 n14 n13 = model=s2bmod

v.vbat n22 n19 = dc=1
equations {
i (n51->n50) +=iscl
iscl: v(n51,n50) = ((v(n5,n51)/(1e-9+abs(v(n5,n51))))*((abs(v(n5,n51)*1e6/42))** 2.5))
}
}
```

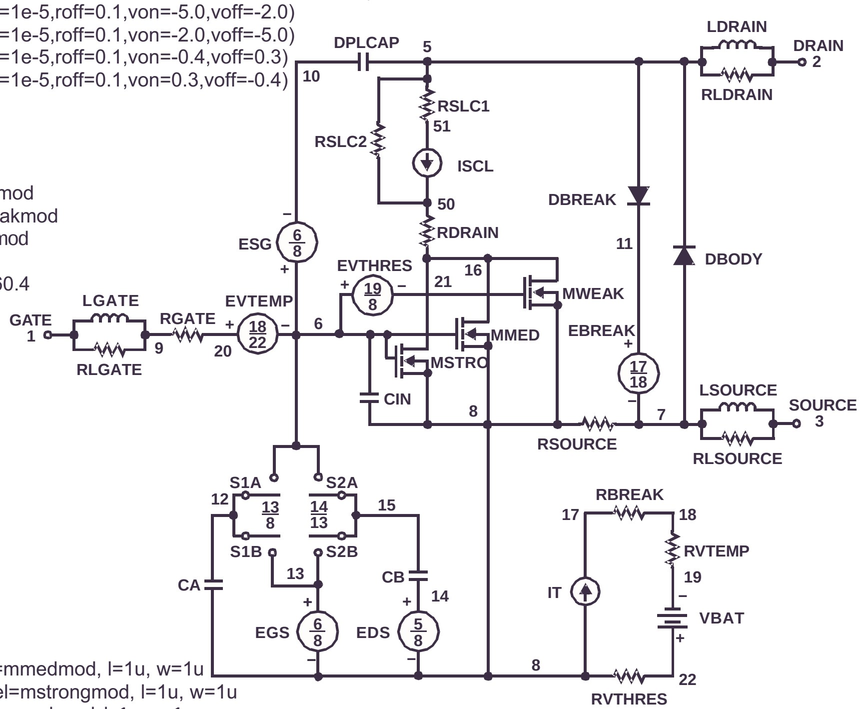


Figure 23. SABER Electrical Model

SPICE / SABER Thermal Model

SPICE Thermal Model

REV 19 July 2002

FDD2582

CTHERM1 TH 6 1.6e-3
CTHERM2 6 5 4.5e-3
CTHERM3 5 4 5.0e-3
CTHERM4 4 3 8.0e-3
CTHERM5 3 2 8.2e-3
CTHERM6 2 TL 4.7e-2

RTHERM1 TH 6 3.3e-2
RTHERM2 6 5 7.9e-2
RTHERM3 5 4 9.5e-2
RTHERM4 4 3 1.4e-1
RTHERM5 3 2 2.9e-1
RTHERM6 2 TL 6.7e-1

SABER Thermal Model

SAB

thermal_c th, tl
{
ctherm.ctherm1 th 6 =1.6e-3
ctherm.ctherm2 6 5 =4.5e-3
ctherm.ctherm3 5 4 =5.0e-3
ctherm.ctherm4 4 3 =8.0e-3
ctherm.ctherm5 3 2 =8.2e-3
ctherm.ctherm6 2 tl =4.7e-2

rrtherm.rtherm1 th 6 =3.3e-2
rtherm.rtherm2 6 5 =7.9e-2
rtherm.rtherm3 5 4 =9.5e-2
rtherm.rtherm4 4 3 =1.4e-1
rtherm.rtherm5 3 2 =2.9e-1
rtherm.rtherm6 2 tl =6.7e-1
}

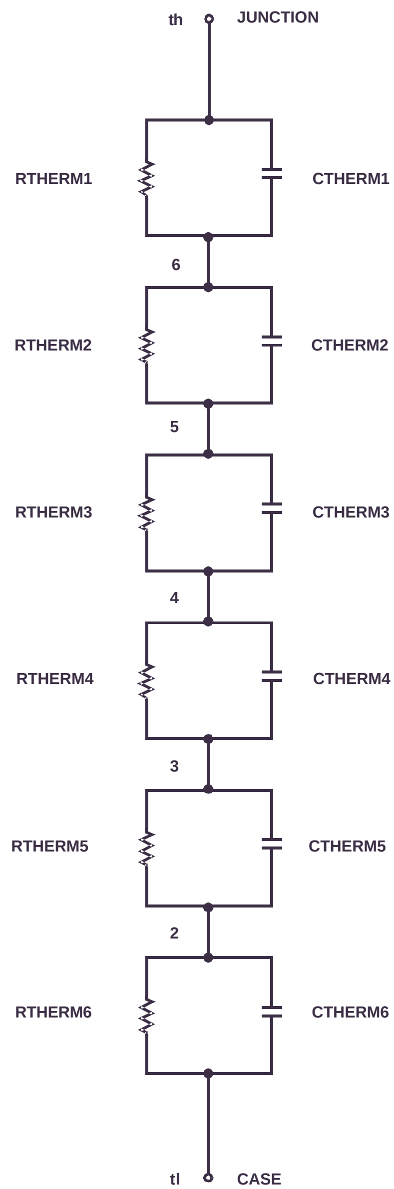


Figure 24. SPICE / SABER Thermal Model

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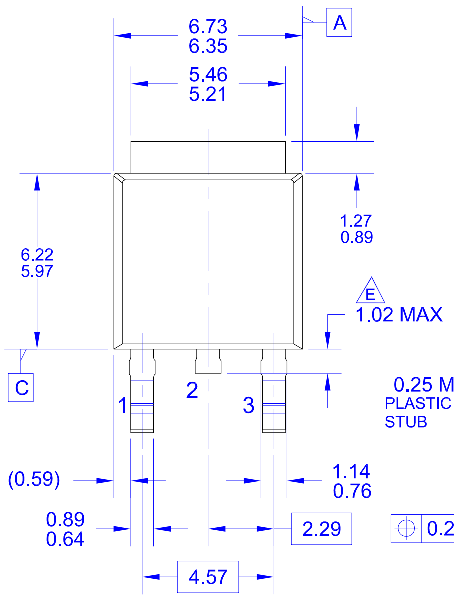
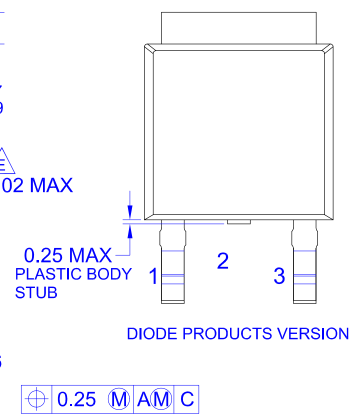
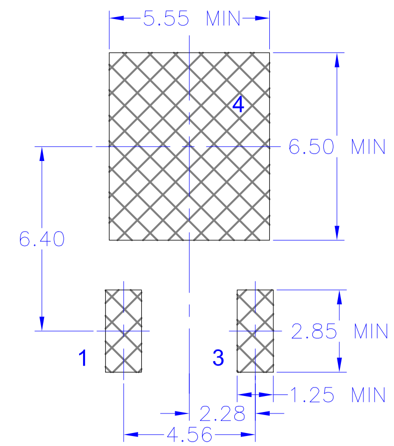
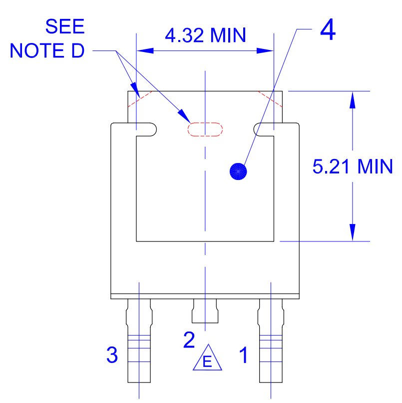


NON-DIODE PRODUCTS VERSION





LAND PATTERN RECOMMENDATION



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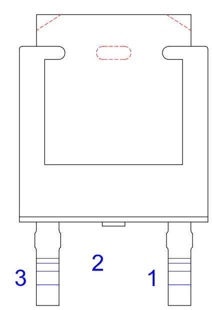
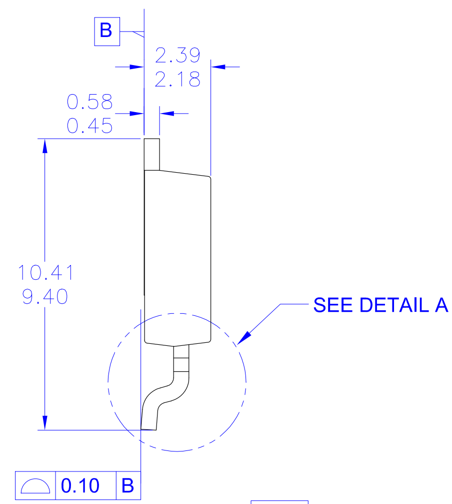
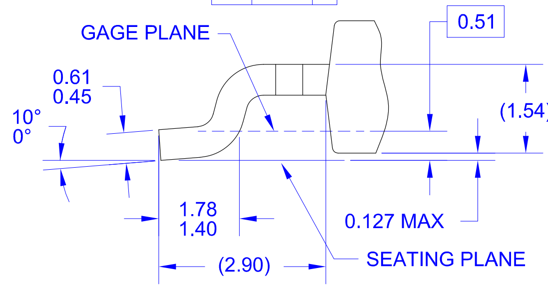


DIODE PRODUCTS VERSION



NOTES: UNLESS OTHERWISE SPECIFIED

A) THIS PACKAGE CONFORMS TO JEDEC, TO-252, ISSUE C, VARIATION AA.
B) ALL DIMENSIONS ARE IN MILLIMETERS.
C) DIMENSIONING AND TOLERANCING PER ASME Y14.5M-2009.
D) SUPPLIER DEPENDENT MOLD LOCKING HOLES OR CHAMFERED CORNERS OR EDGE PROTRUSION.
E) TRIMMED CENTER LEAD IS PRESENT ONLY FOR DIODE PRODUCTS
F) DIMENSIONS ARE EXCLUSIVE OF BURSS, MOLD FLASH AND TIE BAR EXTRUSIONS.
G) LAND PATTERN RECOMENDATION IS BASED ON IPC7351A STD TO228P991X239-3N.



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